SEMICONDUCTOR TEST SYSTEM WITH TIME CRITICAL SEQUENCE GENERATION USING GENERAL PURPOSE OPERATING SYSTEM

Abstract of the Disclosure

A semiconductor test system is capable of time critical

5   sequence generation using a general purpose operating system. The semiconductor test system includes a tester hardware for providing power sources and test patterns to a device under test, a host computer operated by a general purpose operating system, a configuration software for computing configuration

10   data and timing data based on a test program, a device driver for providing a power trigger and a signal trigger to the tester hardware, and a hardware timer for producing an interrupt signal. The device driver causes to start the test pattern and to deactivate the power sources upon receiving

15   the interrupt signal.

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